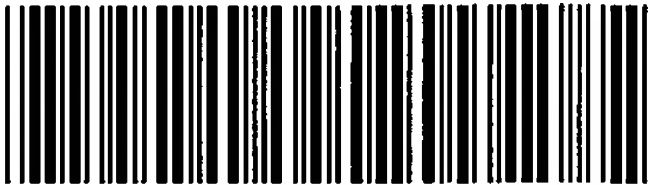


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/624,513	KAYAMA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Feben M. Haile	2616	

SEARCHED			
Class	Subclass	Date	Examiner
370	335	4/14/2007	FH
370	342	4/14/2007	FH
370	441	4/14/2007	FH
370	479	4/14/2007	FH
455	522	4/14/2007	FH

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Seach: cdma, power control, sir, upstream, forward	4/14/2007	FH